

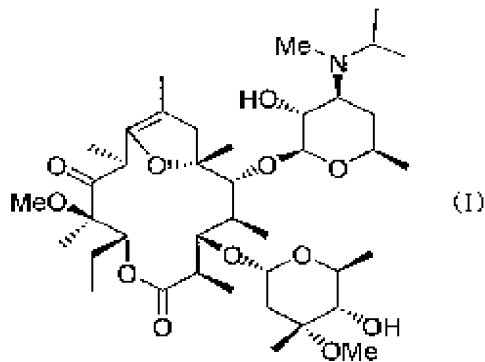
AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1-24. (Cancelled)

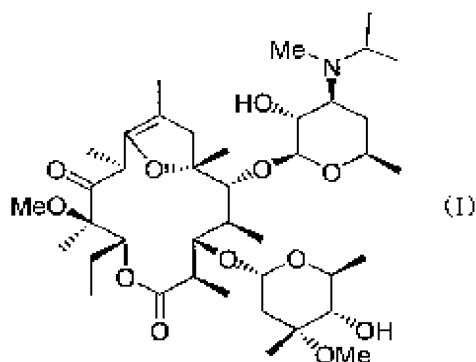
25. (Currently Amended) A process for preparing a hemifumarate anhydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, and a residual solvent content of 1500 ppm or below, said process comprising:

treating Crystal Form C at 20-40°C in a mixed solvent of ethyl acetate and water to obtain Crystal Form E, ~~and~~

stirring the Crystal Form E in a mixed solvent of ethyl acetate and water at less than 20°C to obtain a hemifumarate crystal of a compound of formula (I):

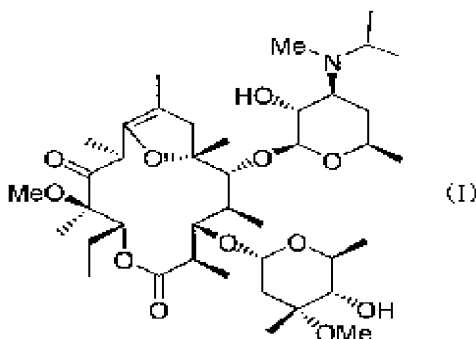


characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°, and

drying the hemifumarate crystal under reduced pressure to obtain said hemifumarate anhydrate,

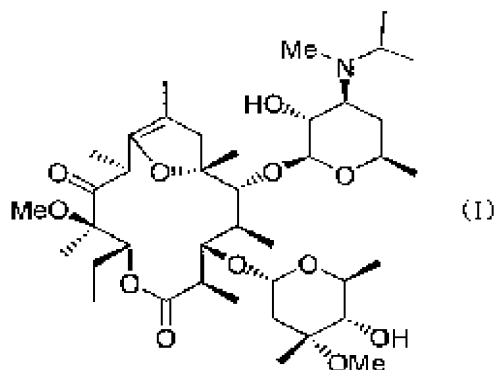
wherein Crystal Form E is a hemifumarate ~~hydrate~~ of a compounds formula (I) that has 2-theta angle positions in the powder X-ray diffraction patterns of 5.6° and 10.4° as measured by X-ray diffractometry.

26. (Currently Amended) Crystal Form of a hemifumarate anhydrate of a compound of formula (I):



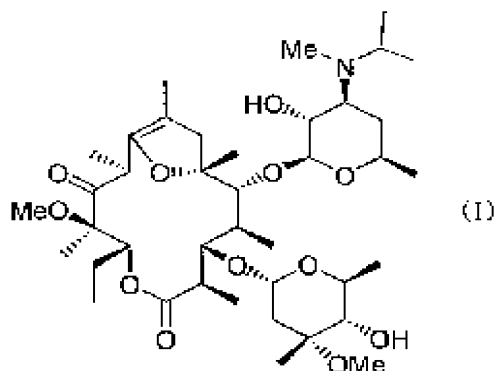
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, and a residual solvent content of 1500 ppm or below, which crystal is obtained by the process of claim 25.

27. (Currently Amended) A process for preparing a hemifumarate hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, and a residual solvent content of 1500 ppm or below, said process comprising:

stirring Crystal Form E in a mixed solvent of ethyl acetate and water to obtain a hemifumarate crystal of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction ~~patterns~~ pattern of 6.6° and 8.5°, ~~and~~

drying the hemifumarate crystal under reduced pressure to obtain a hemifumarate anhydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° , 13.5° and 14.2° , and

conditioning the anhydrate to obtain said hemifumarate hydrate;

wherein Crystal Form E is a hemifumarate hydrate of a compound of formula (I) that has 2-theta angle positions in the powder X-ray diffraction pattern of 5.6° and 10.4° as measured X-ray diffractometry.

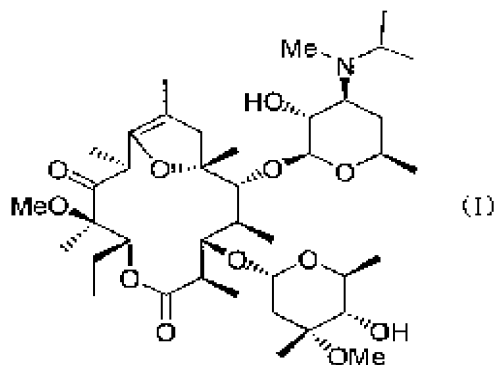
28. (Currently Amended) A-Crystal Form of a hemifumarate hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2° , and a residual solvent content of 1500 ppm or below, which crystal is obtained by the process of claim 27.

29-34. (Cancelled)

35. (Currently Amended) Crystal Form D of a hemifumarate hydrate of a compound of formula (I):



which crystal is obtained via Crystal Form E and a residual solvent content of 1500 ppm or below,

wherein Crystal Form E is a hemifumarate ~~hydrate~~ of a compound of formula (I) that has 2-theta angle positions in the powder X-ray diffraction pattern of 5.6° and 10.4° as measured X-ray diffractometry.